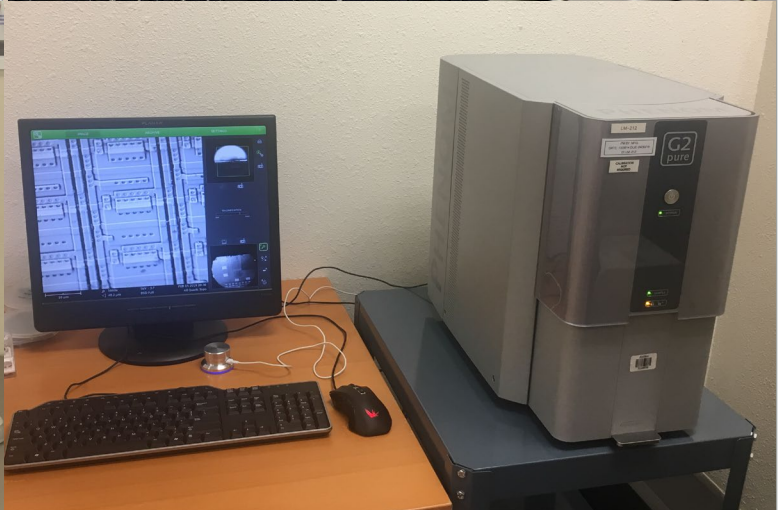
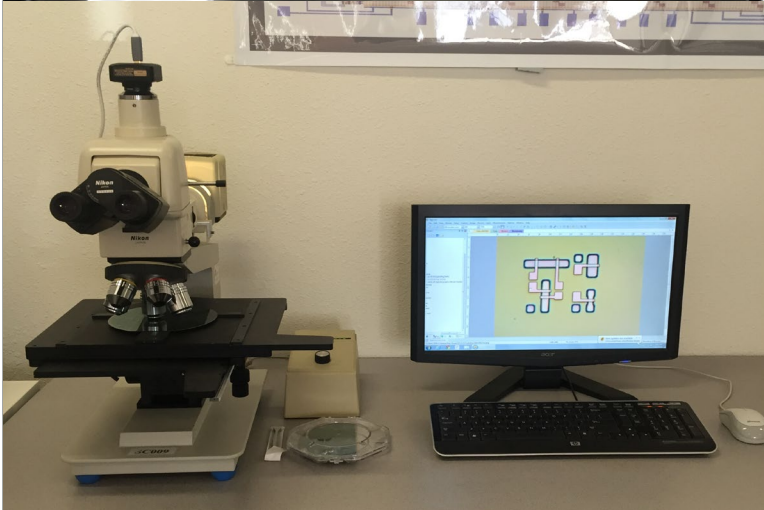
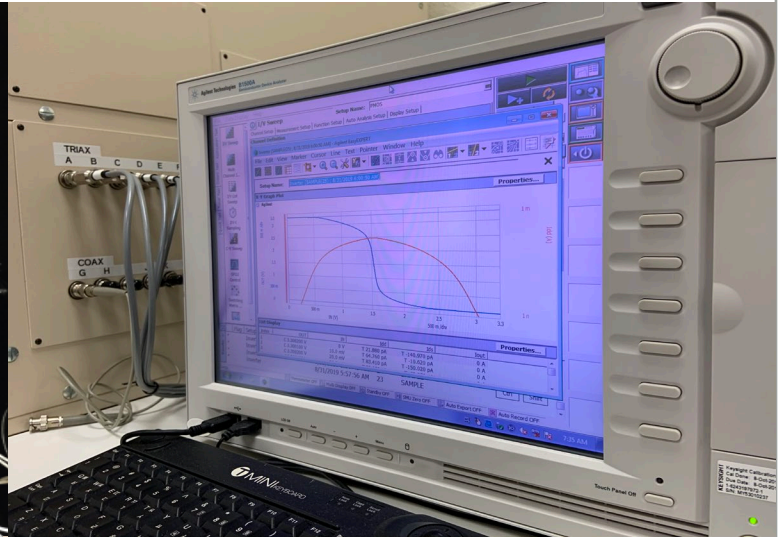
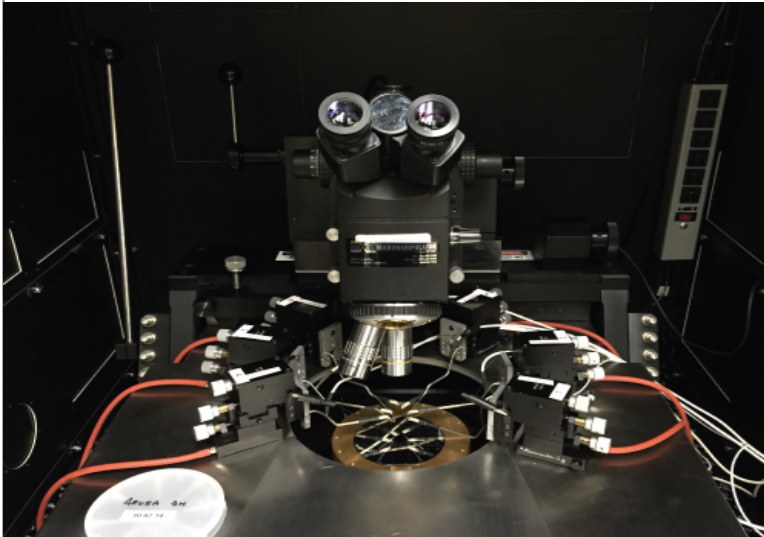


Device Characterization Service

For a prototype-level production, research labs, and start-ups



We provide device measurement services with Probe Station, Parameter Analyzer, OM, and SEM.

Stratio, Inc.
1863 Concourse Dr.
San Jose, CA 95131
sales@stratiotechnology.com

Capability

Probe Station: Micromanipulator MM8060

Parameter Analyzer: Keysight B1500A

Microscope + Camera: Nikon Optiphot 150 + Amscope MU500

Scanning Electron Microscopy (SEM) : Phenom Pure (below 10 nm resolution)

Pricing

Please contact sales@stratiotechnology.com for detailed quotation.